

PATENT

Case Docket No. IMEC215.001C1

Date: August 28, 2003

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s) : Meuris, et al.  
Appl. No. : 10/630,439  
Filed : July 29, 2003  
For : METHOD AND APPARATUS  
FOR SIMULATING  
PHYSICAL FIELDS  
Examiner : Unknown  
Group Art Unit : Unknown

I hereby certify that this correspondence and all marked attachments are being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on

August 28, 2003

(Date)

Eric M. Nelson, Reg. No. 43,829

TRANSMITTAL LETTER

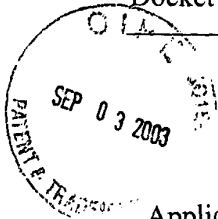
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Enclosed for filing in the above-identified application are:

- (X) An Information Disclosure Statement.
- (X) A PTO Form 1449 listing 21 references, no enclosures.
- (X) The Commissioner is hereby authorized to charge any additional fees which may be required, or credit any overpayment, to Account No. 11-1410.
- (X) Return prepaid postcard.

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## INFORMATION DISCLOSURE STATEMENT

Applicant : Meuris, et al.  
App. No. : 10/630,439  
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For : METHOD AND APPARATUS FOR  
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Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Enclosed is form PTO-1449 listing references that were previously disclosed to or cited by the Patent and Trademark Office in the prosecution of U.S. patent application No. 09/888,868, filed June 25, 2001, which is the parent of this Continuation application, and is relied upon for an earlier filing date under 35 U.S.C. § 120. Copies of the references are not submitted pursuant to 37 C.F.R. § 1.98(d).

This Information Disclosure Statement is being filed within three months of the filing date of this application and no fee is required in accordance with 37 C.F.R. § 1.97(b)(1), (b)(2), or (b)(4).

Respectfully submitted,

KNOBBE, MARTENS, OLSON & BEAR, LLP

Dated: Aug. 28, 2003

By: 

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FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. IMEC215.001C1	APPLICATION NO. 10/630,439
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Meuris, et al.	
		FILING DATE July 29, 2003	GROUP Unknown

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
	1.	6,051,027	4/2000	Kapur et al.			
	2.	6,064,810	05/16/00	Raad et al.			
	3.	6,137,492	10/24/00	Hoppe			
	4.	6,266,062	07/24/01	Rivara			
	5.	6,453,275	9/2002	Schoenmaker			

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)	
	6.	Albanese, R., et al., "Numerical Procedures for the Solution of Nonlinear Electromagnetic Problems", IEEE Transactions on Magnetics, Vol. 28, No. 2, March 1992. XP-002181720
	7.	E.M. Buturla, et al., "Finite-Element Analysis of Semiconductor Devices: The Fielday Program", IBM Journal on Research and Development, Vol. 25, No. 4, pgs. 218-231, July 1981.
	8.	A. De Mari, "An Accurate Numerical One-Dimensional Solution of the p-n Junction Under Arbitrary Transient Conditions", Solid State Electronics, Vol. 11 pgs. 1021-1053, 1968.
	9.	H.K. Dirks, "Quasi-Stationary Fields for Microelectronic Applications", Electrical Engineering, Vol. 79, pgs. 145-155, 1996.
	10.	A. F. Franz, et al., "Finite Boxes- A Generation of the Finite-Difference Method Suitable for Semiconductor Device Simulation", IEEE Trans. On Electronic Devices, Vol. ED-30, No. 9, September 1983.
	11.	Grosso et al., "The multilevel finite element method for adaptive mesh optimization and visualization of volume data", <i>Proceedings Visualization '97</i> , pp. 387-394 (1997)
	12.	H. Hasegawa, et al., "Properties of Microstrip Line on Si-SiO System", IEEE Trans. On Microwave Theory and Techniques, Vol. MTT-19, No. 11, November 1971.
	13.	Hoppe, H., "Smooth view-dependent level-of-detail control and its application to terrain rendering", <i>Proceedings Visualization '98</i> , pp. 35-42 (1998)
	14.	Klingbell, et al., "A local mesh refinement algorithm for the FDFD method using a polygonal grid", <i>IEEE Microwave and Guided Wave Letters</i> , 6(1):52-54 (1996)
	15.	Kulke, et al., "Multigrid technique with local grid refinement for solving static field problems [RF circuits]", <i>IEEE MTT-S International Microwave Symposium Digest</i> , Vol. 1, pp. 29-32 (1998)
	16.	S.E. Laux, "Technique for Small Signal Analysis of Semiconductor Devices" IEEE Trans. On Computer Aided Design, Vol. CAD-4, No. 4, October 1985.
	17.	Monorchio, et al., "A novel subgridding scheme based on a combination of the finite-element and finite-difference time-domain methods", <i>IEEE Transactions on Antennas and Propagation</i> , 46(9):1391-1393 (1998)
	18.	Nyka, K., et al., "Combining Function Expansion and Multigrid Method for Efficient Analysis of MMIC's", 11 <sup>th</sup> International Microwave Conference, Warsaw, Poland, May 1996. XP-001033645
	19.	D.L. Scharfetter, et al., "Large-Signal Analysis of a Silicon Read Diode Oscillator", IEEE Trans. on Electronic Devices, Vol. ED-16, No. 1, January 1969.
	20.	K.G. Wilson, "Confinement of Quarks", Physical Review, Vol. D, No. 8, October 15, 1974.
	21.	Zheng, Ji, et al., "CAD-Oriented Equivalent-Circuit Modeling of Off-Chip Interconnects on Lossy Silicon Substrate", IEEE Transactions on Microwave Theory and Techniques, Vol. 48, No. 9, September 2000. XP-002181721

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EXAMINER	DATE CONSIDERED
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.	